



**Laura Mascio Kegelmeyer**

**CASIS Signal and Imaging Workshop  
November 16-17, 2006**

UCRL-PRES-226124

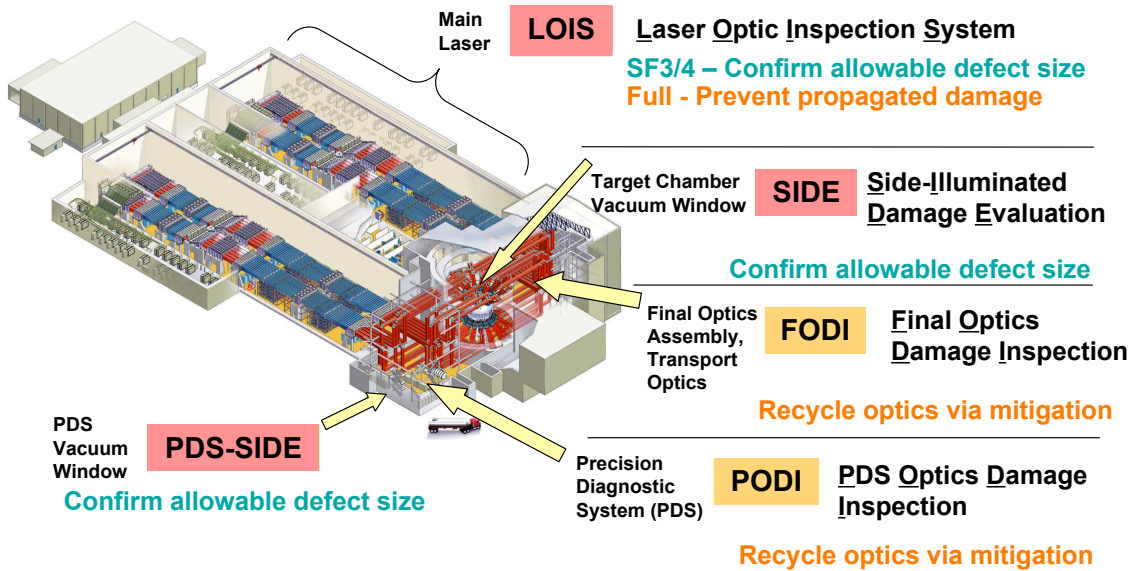
This work was performed under the auspices of the U.S. Department of Energy by University of California, Lawrence Livermore National Laboratory under Contract W-7405-Eng-48.

**Optics Inspection: Interdisciplinary effort merges engineering,  
computer science, physical optics theory, and customer interface**



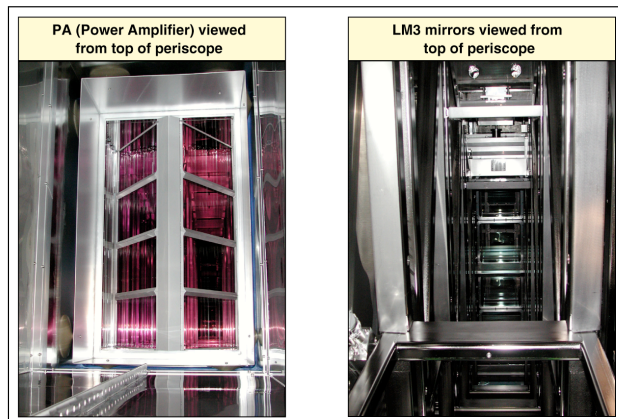
- **Algorithms & Application Development:** Steve Glenn, Judy Liebman
- **FRODO TechBase:** Anthony Azevedo, Mina Bionta, Barry Chen, Aseneth Lopez
- **Summer Projects:** Ketrina Yim, Jack Tzeng, Philip Fong, Dan Potter, John Pate
- **Image Acquisition Software:** Vicki Miller Kamm
- **Physical Optics theory:** Erlan Bliss and Thad Salmon
- **Systems Engineering:** Steve Azevedo, Scott Burkhart, Walter Ferguson
- **Web, Java GUI Development:** John Carlson, Stephanie Daveler
- **Eng/Scientists/Customers:** Jim Chang, Chris Choate, Alan Conder, Chris Haynam, Mike Nostrand, Tom Parham, Rahul Prasad, Mary Spaeth, Pam Whitman, Shot Directors and Control Room Operators.
- **Support & feedback:** testers, configuration management team, system administrators, database administrators

NIF has thousands of optics on the beamlines which must be inspected after every shot



On-beamline inspections can be like looking through a house of mirrors

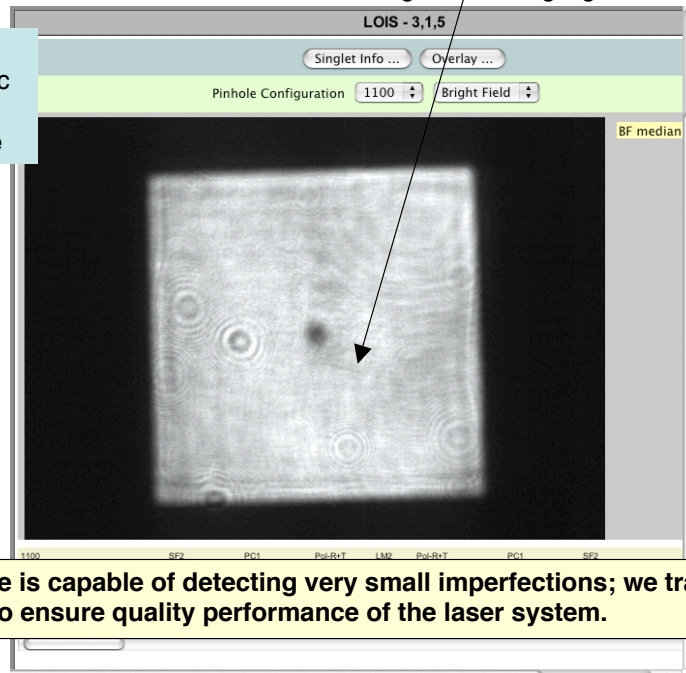
- Focusing on clear glass can be tricky
- Images are relayed to camera through mirrors/periscope, spatial filters and other lenses and optics
- Must keep track of orientation



**The LOIS inspection system for the Main Laser has mirrors, relay optics and intervening glass. Light scattering sites can still be detected**

Real light scattering sight

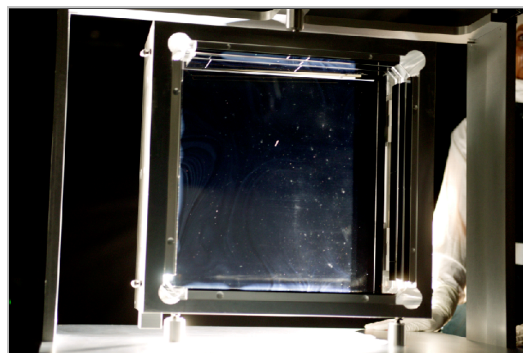
We must detect the site, identify the optic on which it resides and estimate its size



Analysis software is capable of detecting very small imperfections; we track these over time to ensure quality performance of the laser system.

**In addition, every optic is inspected (off-beamline) before and after going on the beamline**

- Verify manufacturing specifications
- Pass/Fail quality of coatings
- Confirm Conditioning
- Mitigation
- Refurbishment



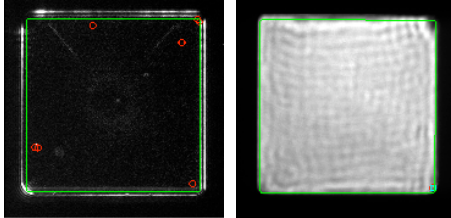
**To track the evolution of a defect requires tracking a variety of conditions:**

- Illumination settings
- Exposure times
- Operator-specific methods
- Orientation!

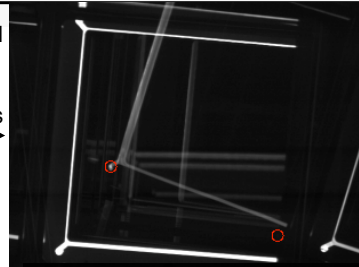
Most on-beamline and off-beamline images go through the same “one” algorithm (Local SNR for each pixel in image) with specified parameters



Beamline commissioning



High Level Reporting for Shot Readiness

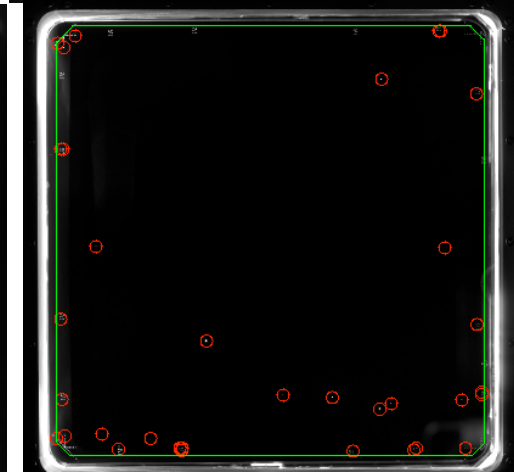
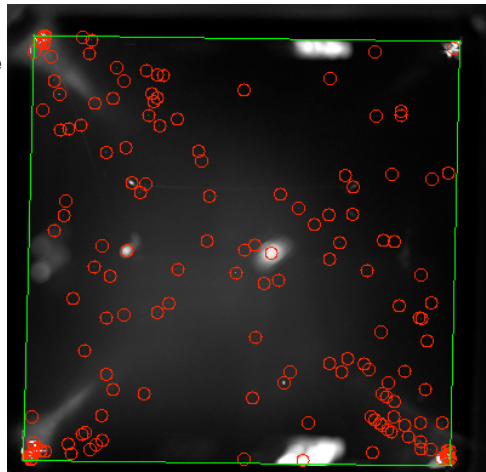


The National Ignition Facility

Off-line QA Conditioning Validation

Detect tiny flaws online

Interface to prediction codes for recycling optics



**Example of 1 (manufactured) defect imaged from online to offline inspections**



**SIDE (Online image of TCWV)**

-Check for damage exceeding 1 mm.

Portion of SIDE image (640x480) 1 mm / pixel

**DMS-OPL (Damage Mapping System - Optics Processing Lab)**

-Confirm size and location of surface flaws - 97 microns per pixel

Portion of laboratory image of full optic (4kx4kx2) 97 microns / pixel. [OPL 750020]

**CIM (Conditioning, Initiation & Mitigation)**

-Test and condition the optic with increasing laser energies  
-Scattering sites smoothed (mitigated) with a CO2 laser

**Micrographs**

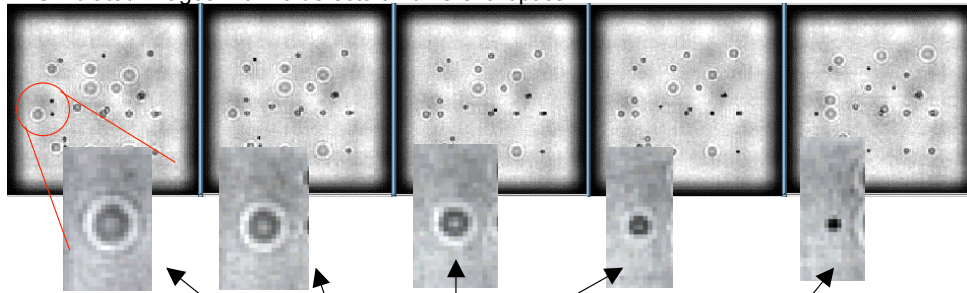
- Evaluate “true” size of flaws for calibration and validation - 6 microns per pixel

Micrograph / “Truth” Image = 1/16th full size 6 microns/pixel

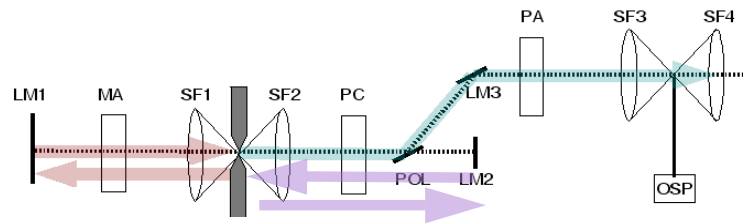
**We may be able to find some defects by using their out-of-focus rings to estimate location and size -- Finding Rings Of Damage on Optics**



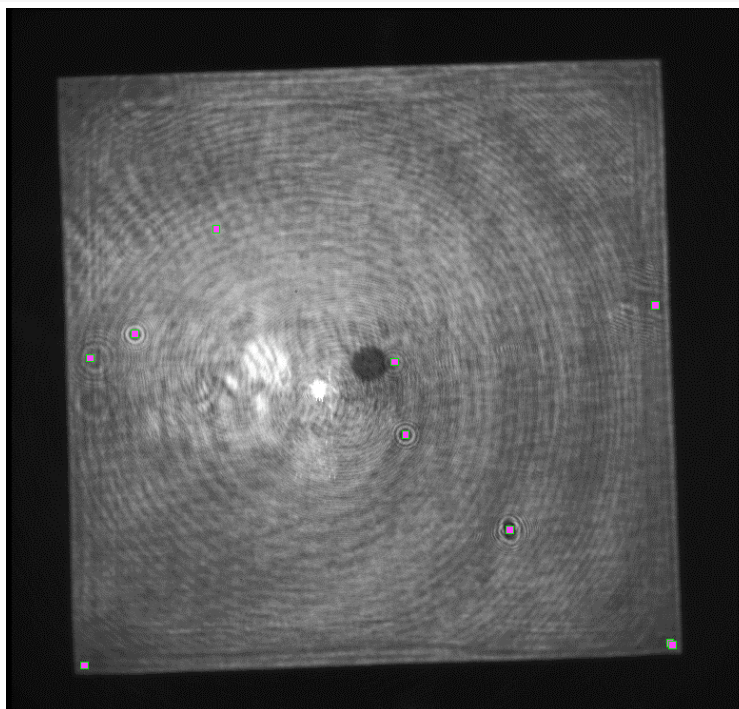
Simulated images with 15 defects on different "optics"



1100	SF2	PC1	PoI-R+T	LM2	PoI-R+T	PC1	SF2			
1110	SF1	MA11	MA8	MA5	MA2	LM1	MA2	MA5	MA8	MA11
1111		SF2	PC1	PoI-R	LM3		PA1	PA3	PA5	PA7
	6.45	6.8	7.16	7.51	7.85	8.22	8.57	8.92	9.28	



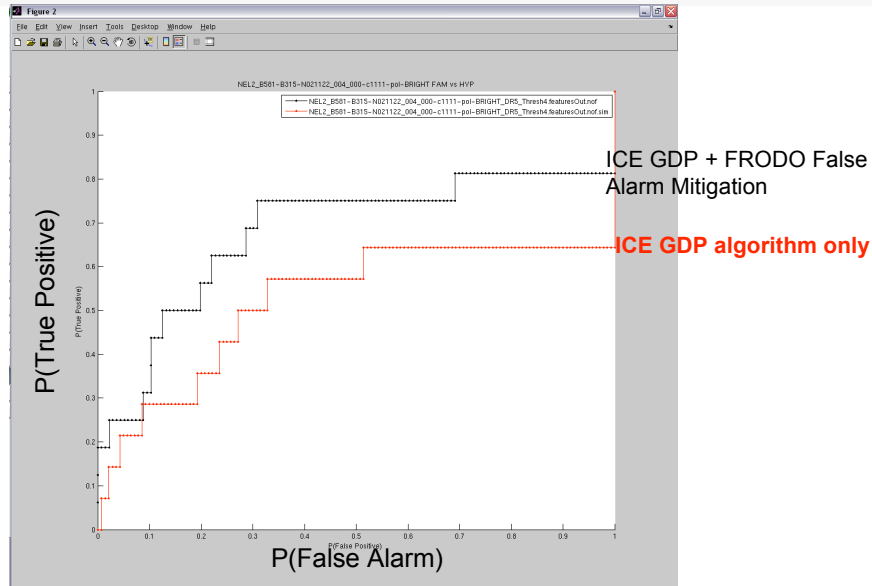
**FRODO (based on ICE GDM\*) was able to find diffraction rings on NIF Final Optics by tuning 4 adjustable parameters**



\*Image Content Engine

Gradient Direction Matching

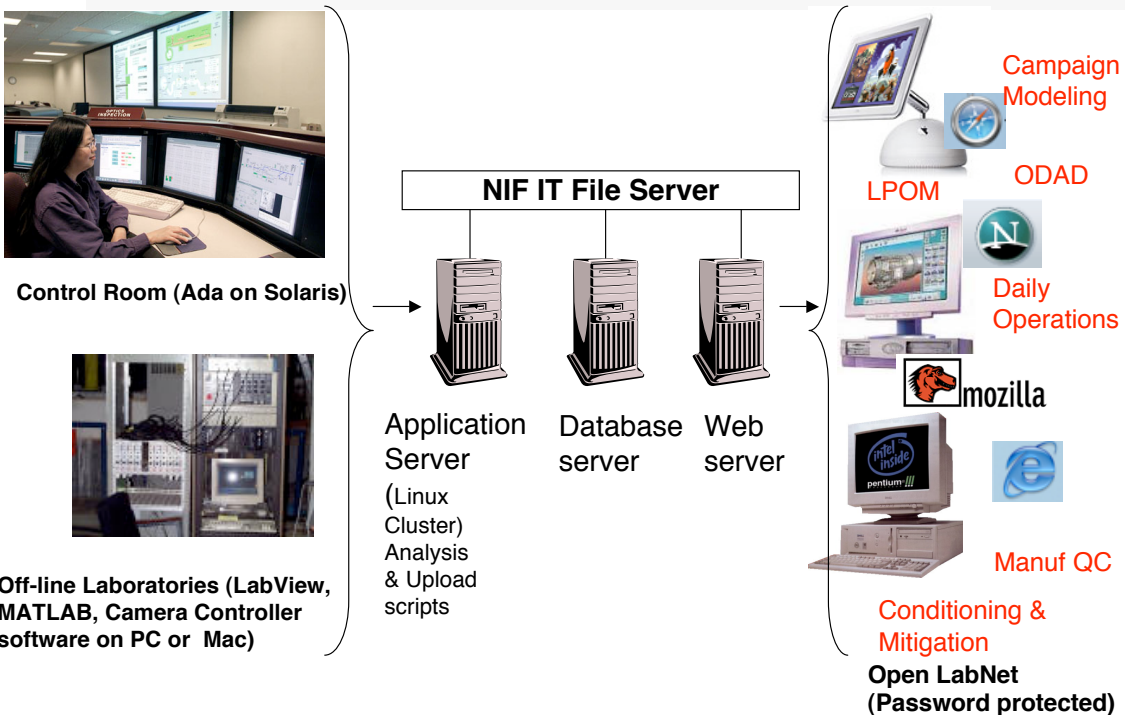
**APPSPACK\* optimized FRODO parameters;  
Receiver Operating Characteristic curves provided performance metrics**



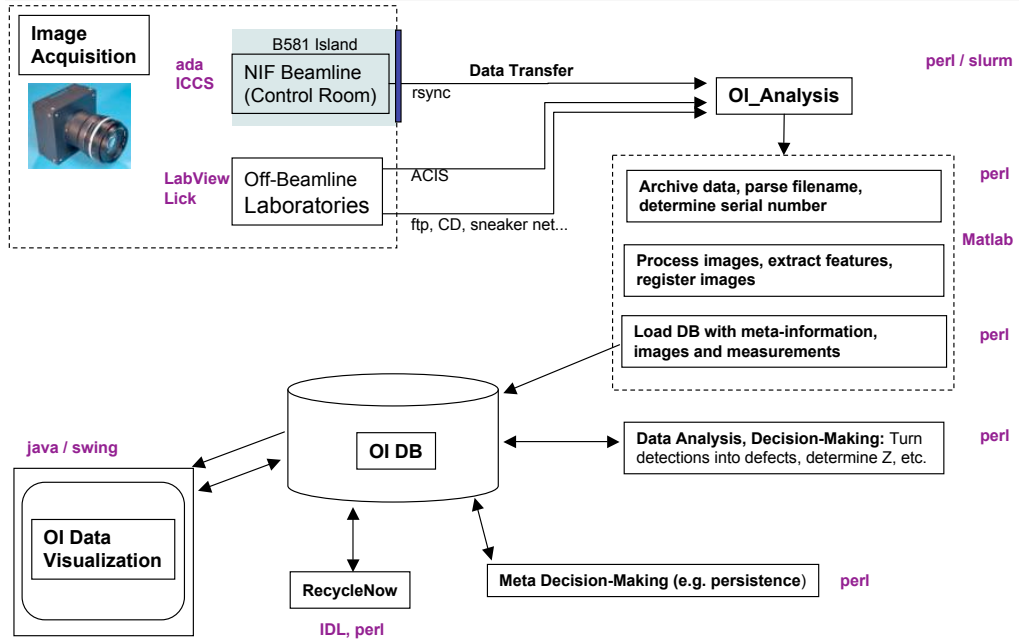
\*APPSPACK (G Gray, T Kolda; Sandia, CA): derivative-free optimization software for solving nonlinear unconstrained and bound-constrained optimization problems, with possibly noisy and expensive objective functions.

How OI Analysis is used in practice for NIF....

**Our client-server design is a robust and flexible tool that allows many customers to access/display results as needed for many different purposes**



# Data Flow for NIF Optics Inspection



A java-based visualization application allows users to view inspection results from a birds-eye view or in great detail



Close-up of analysis results for a commissioning fiducial

## OI Scaling to NIF: The amount of data storage will quickly become large



Inspection Type	Images per dataset	Estimated Image Size (GB)	Size per dataset (GB)	Anticipated no. datasets	Interval	Inspections Per Month	Size per beam per Month (GB)	Partial NIF Total for one year (GB)	Full NIF Total for one year (GB) *
FODI	16	0.032	0.512	1	per day	20	10.24	983.0	23,593.0
NODI	16	0.032	0.512	0	per week	0	0.00	0.0	0.0
PODI	16	0.032	0.512	1	per week	4	2.05	24.6	24.6
SIDE	4	0.000	0.001	1	per shot	20	0.02	2.2	52.7
LOIS	58	0.001	0.057	2	per week	8	0.91	87.0	2,088.0
Sub-LOIS (SF3, SF4)	10	0.001	0.010	1	per shot	20	0.20	18.8	450.0
OPL (DMS maps)+ FADLib	2	0.032	0.064	500	per year	n/a	n/a	32.0	32.0
CIM	12	0.032	0.384	250	per year	n/a	n/a	96.0	96.0
PSDI			0.100	350	per year	n/a	n/a	35.0	35.0
IMS	18	0.073	1.318	250	per year	n/a	n/a	329.6	329.6
Calib (micrographs)	10	0.001	0.010	45	per year	n/a	n/a	0.4	0.4
<b>Total Storage Needed</b>								<b>1,608.6</b>	<b>26,701.3</b>

On-line  
Off-line

\* Size estimates are for early NIF (FY '09 - FY '10)

**Summary**

- 27 TBytes/year (50 if full FODI) – ~6000 DVD's
- NIF Ops (/nif) has ~6 TByte now
- 300 GB drives are \$300 now (Maxtor) or \$1/GB
- Archival plans are being made with NIF IT



## OI Analysis supports on-beamline inspections for shot readiness and optics recycling as well as off-beamline for QA, conditioning, validation...



- Automated inspection for images from 9 camera systems on the NIF beamline and 11 offline. (One fundamental algorithm to analyze them all.) Phil Fong
- Track defects on thousands of optics through their lifetime (across different camera systems). Detect and measure defects over a range of sizes to assure quality performance and safety. Alan Conder  
Judy Liebman
- We can keep up with speed requirements by expanding our Linux cluster for parallel analysis of all on-beamline and offline systems. Steve Glenn
- Image analysis runs on an application server and all images and results are stored in a database.
- Java-based visualization application can be downloaded from any browser. It allows each customer to review results appropriately via dynamic database queries.